

<b>Search Notes</b> 				<b>Application/Control No.</b> 10/784,193	<b>Applicant(s)/Patent under Reexamination</b> OKUI, YOSHIAKI	
<b>Examiner</b> Pia F. Tibbits				<b>Art Unit</b> 2838		
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
Class	Subclass	Date	Examiner		DATE	EXMR
307	66					
	64					
	37					
320	138					
363	26					
	37					
<b>INTERFERENCE SEARCHED</b>						
Class	Subclass	Date	Examiner			